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# ESD EDA Verification Flow Applied to Smart Power IC's

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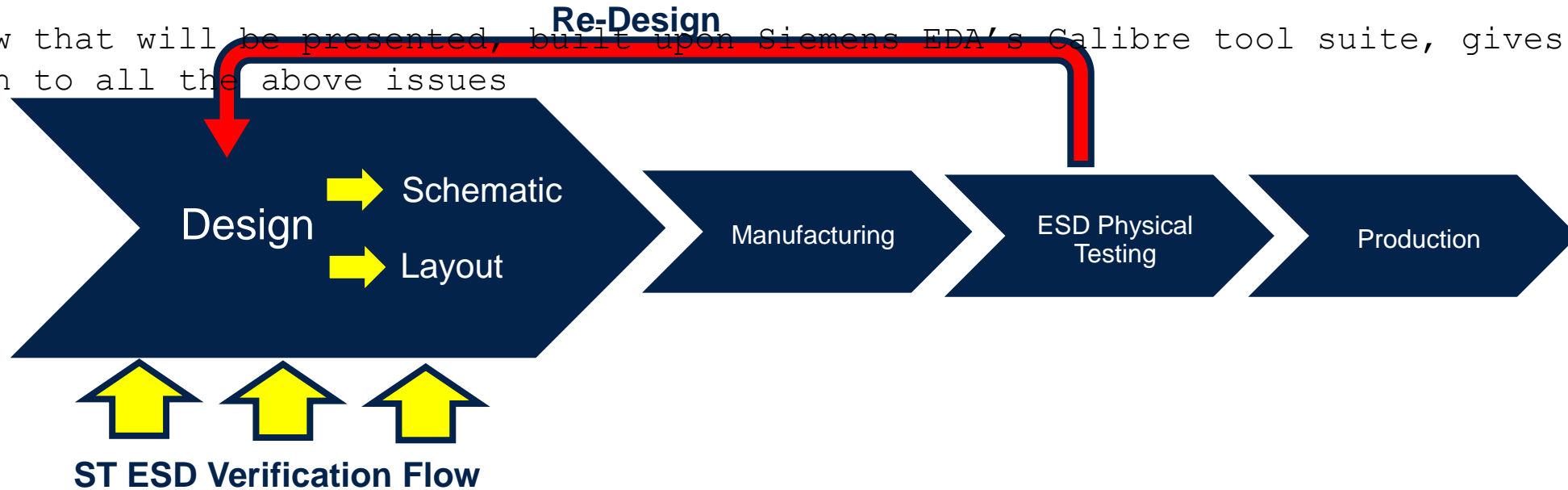
Smart Power Technology R&D

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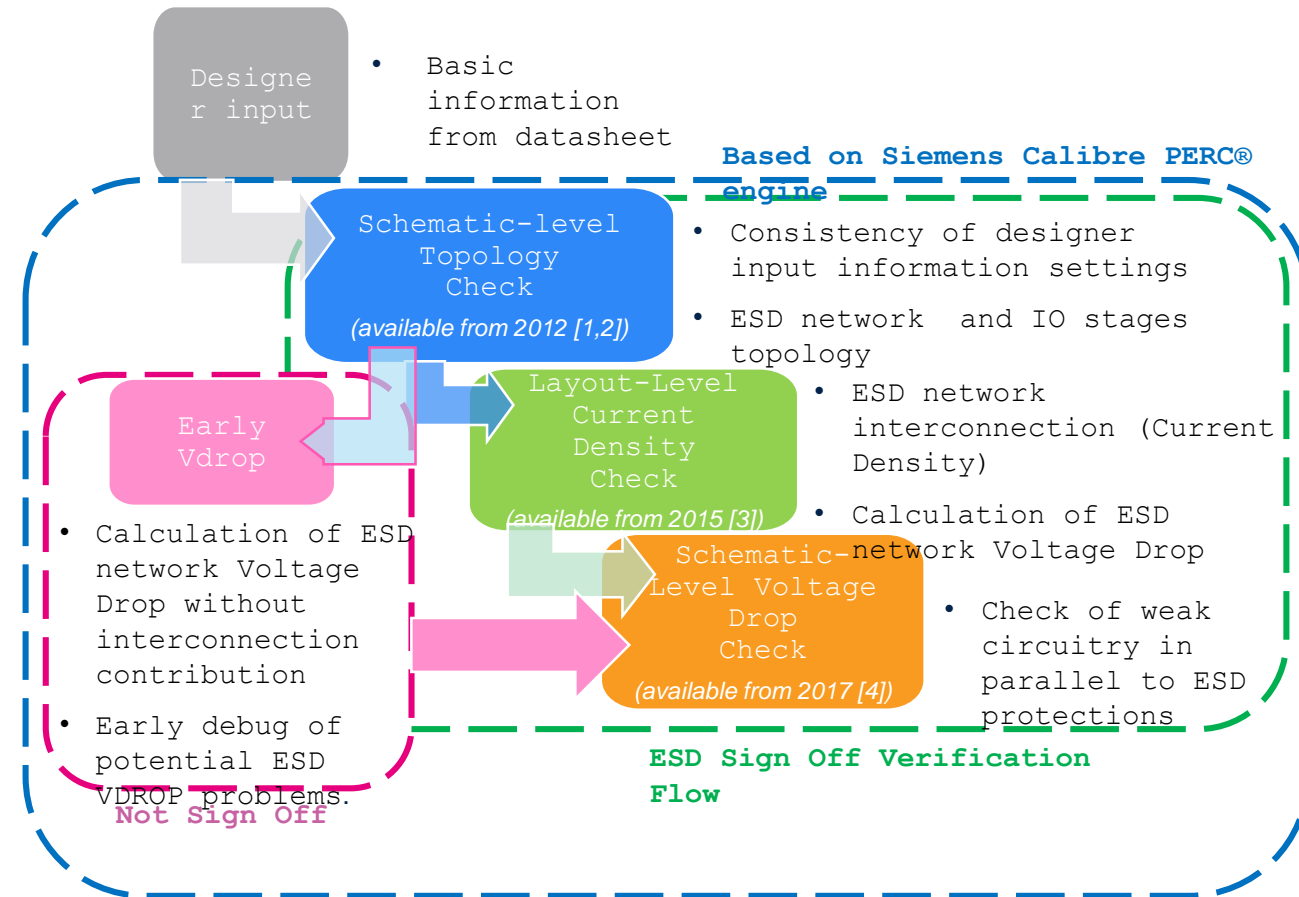
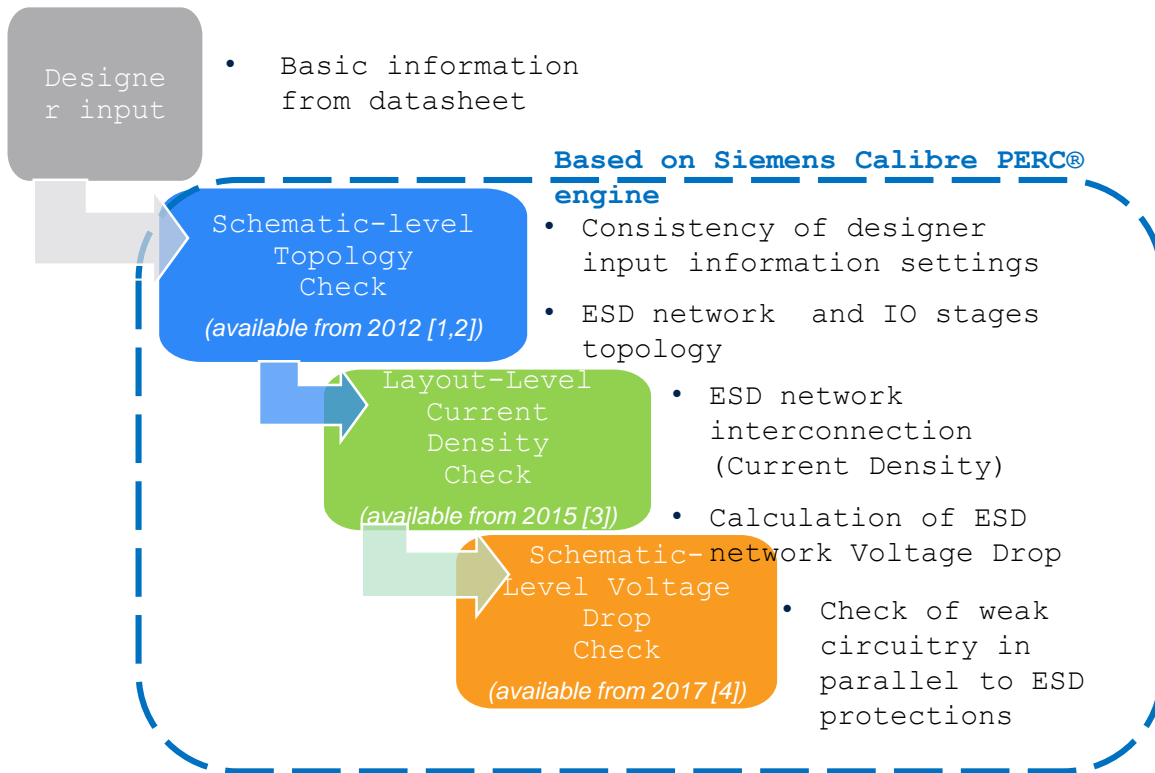
# Why do we need efficient ESD checks on design

- ESD phenomenon can damage any product during manufacturing phase
- Products need to be built robust against ESD before production
- ST ESD workflow is performed at design level (schematic & layout). It detects all issues that may arise during physical testing and prevents redesign → reach product ESD validation asap (money, time, commitment to customer)
- ST ESD workflow can be used at any hierarchical level of the design: cell, IP, ESD ring, full chip level
- **NEW!** Any violation detected during layout validation can be costly to correct, but with the new **EVDROP tool** it is possible to perform a preliminary assessment of ESD network effectiveness at the schematic level and significantly limit such cases
- The flow that will be presented, built upon Siemens EDA's Calibre tool suite, gives a solid solution to all the above issues



# ESD SIGN-OFF Flow

# Improved ESD Checking Flow with in-Design capability

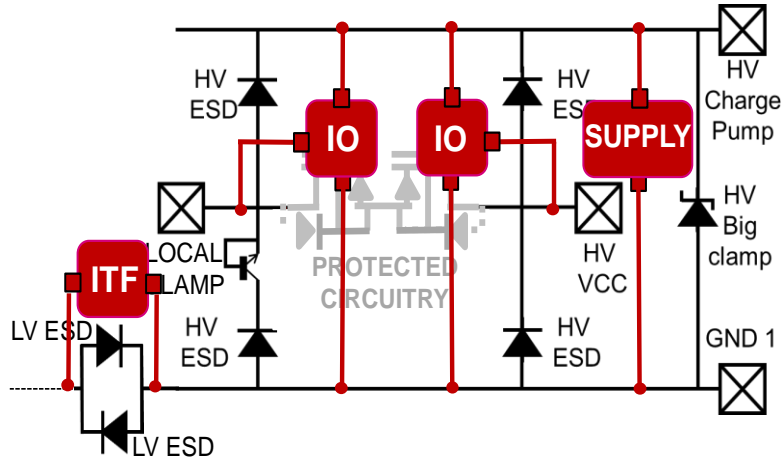


- [1] M. Fragnoli, E. Gevinti, A. Bogani, L. Cerati, "Novel Initialization and Implementation Method for HBM ESD Compliance Automated Check on Smart Power IC's", DAC 2012
- [2] E. Gevinti et al., "HBM ESD EDA Check Method Applied to Complete Smart Power IC's - Functional Initialization and Implementation", Proc. EOS/ESD Symposium 2013
- [3] E. Gevinti et al., "Schematic-Level and Layout-Level ESD EDA Check Methodology Applied to Smart Power IC's - Initialization and Implementation", Proc. EOS/ESD Symposium 2015



# From Schematic to Layout Verification

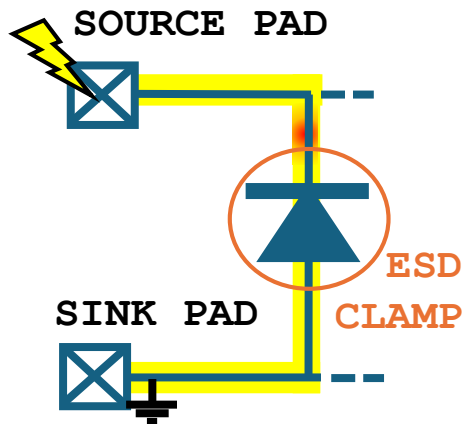
Schematic-level  
Integrity Check



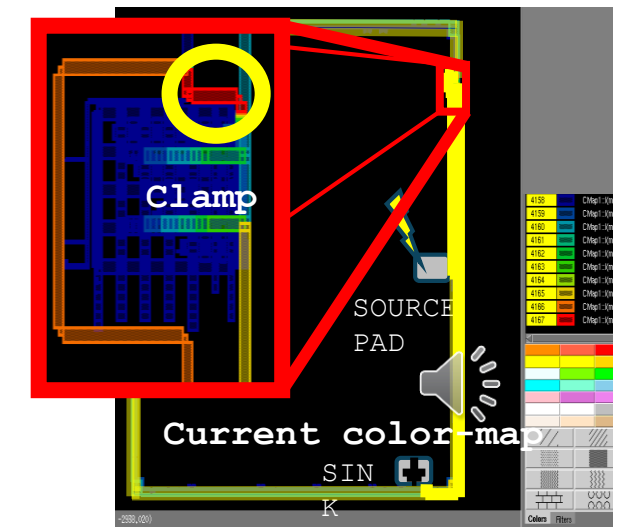
Source Pad	Sink Pad	HBM stress (kV)
IO_x	GND	2
IO_x	VCC	2
VCC	GND	2
...	...	2
IO_GLO	GND	4

- Extracting from schematic each pin functionality (IO / power)
- Information extracted by controllers
- Creating HBM stress pin pairs combination matrix
- Performing all required zaps

Layout-Level  
Current Density Check



Source	A	Sink	B	MaxValue	2.004	HBM	2
Source	C	Sink	D	MaxValue	2.356	HBM	2
Source	E	Sink	F	MaxValue	1.500	HBM	4



Schematic-level Integrity Check



Early Vdrop Checks

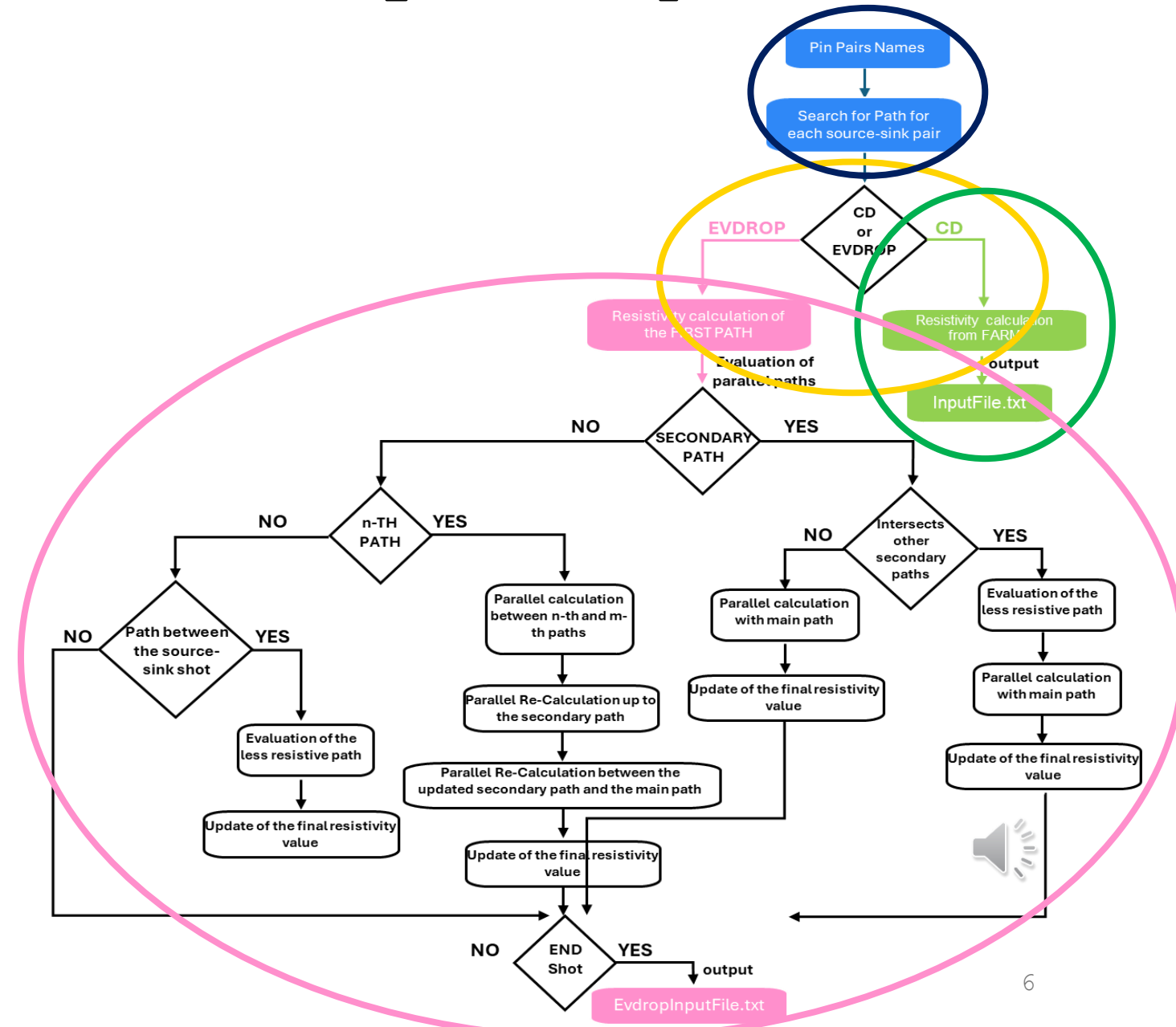
Source	A	Sink	B	MaxValue	2.004	HBM	2
Source	C	Sink	D	MaxValue	2.356	HBM	2
Source	E	Sink	F	MaxValue	1.500	HBM	4

The path search engine is shared by both CD and EARLY VDROP tools. They differ in the calculation of pin-to-pin equivalent resistance for each ESD discharge emulation.

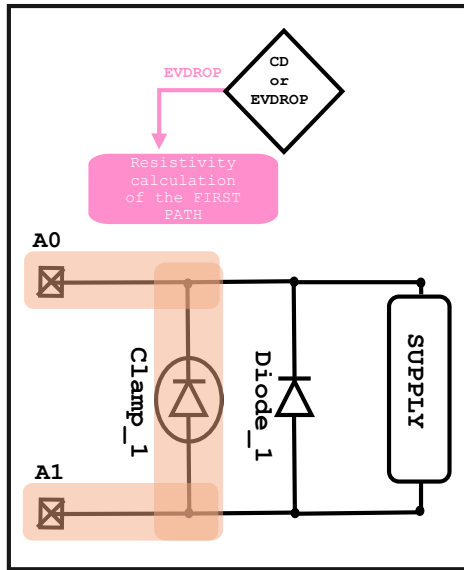
Differences in the two voltage drop output files encompass 3 elements of discrepancy:

- 1) The metallization contribution
- 2) The netlist extraction by layout vs. schematic tool

# Early Vdrop FLOWCHART

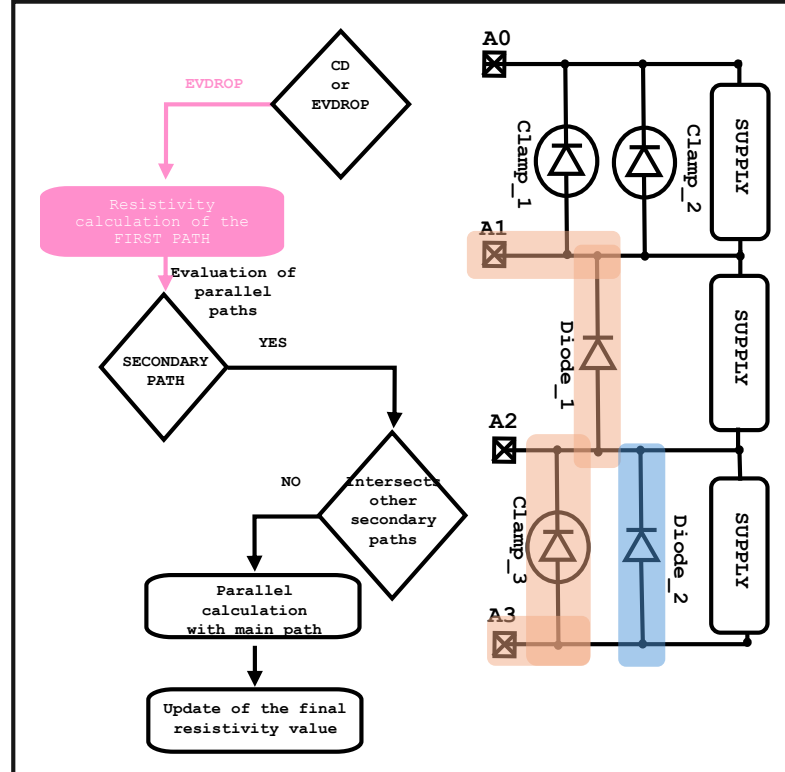


# HOW IT WORKS



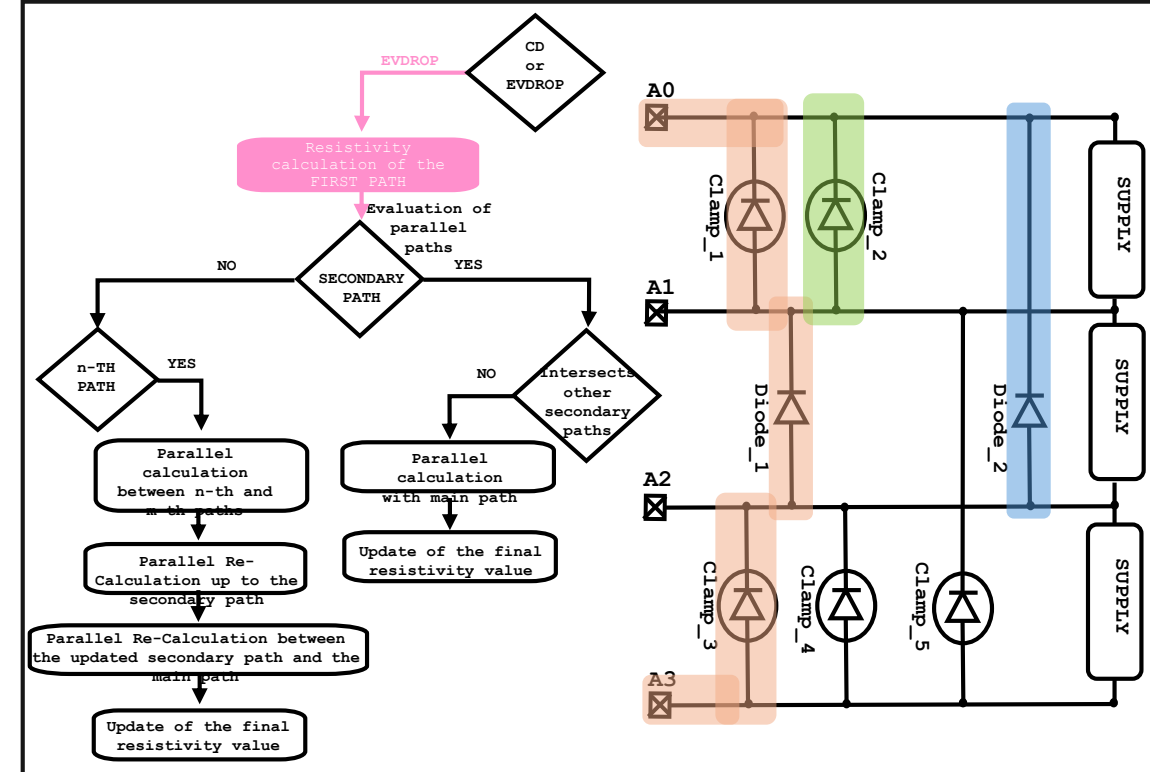
**FIRST PATH: A0 → A1**

first path evaluated between source-sink pair



**FIRST PATH: A3 → A1 + SECONDARY PATH: A3 → A2**

path partially parallel to the first one with entry or exit nets different from the source or sink



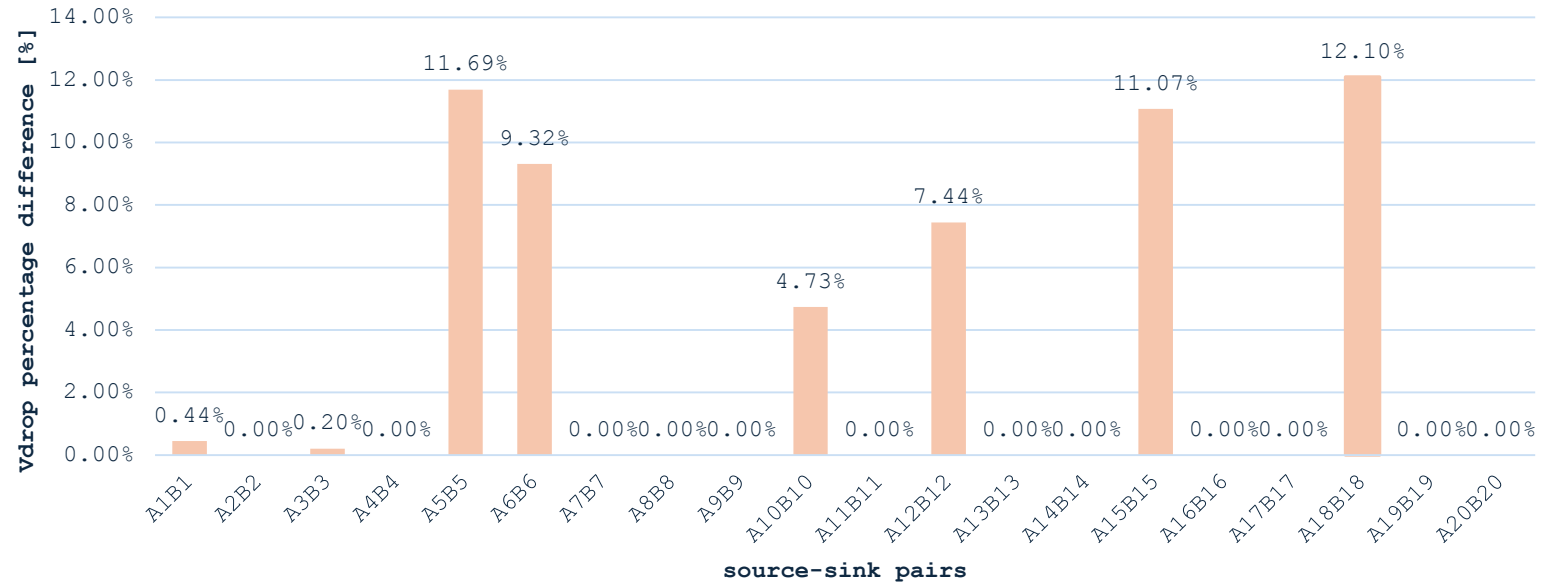
**FIRST PATH: A3 → A0 + N-TH PATH: A2 → A0 + A1 → A0**

path parallel to m-th path, which in turn may be parallel to other paths but ultimately one of these paths will be parallel to the secondary one

# RESULTS ANALYSIS ON A COMPLETE PRODUCT

Source	Sink	Vdrop Percentage Difference	Number of Parallel Paths
A1	B1	0.44%	2
A2	B2	0.00%	Single path
A3	B3	0.20%	2
A4	B4	0.00%	Single path
A5	B5	11.69%	17
A6	B6	9.32%	8
A7	B7	0.00%	Single path
A8	B8	0.00%	Single path
A9	B9	0.00%	Single path
A10	B10	4.73%	4
A11	B11	0.00%	Single path
A12	B12	7.44%	9
A13	B13	0.00%	Single path
A14	B14	0.00%	Single path
A15	B15	11.07%	12
A16	B16	0.00%	Single path
A17	B17	0.00%	Single path
A18	B18	12.10%	13
A19	B19	0.00%	Single path
A20	B20	0.00%	Single path

Discrepancy between EVDROP and CD without metal contribution Voltages



CD vs EVDROP 3 elements of discrepancy:

- 1) Metallization contribution cannot be completely removed from the CD evaluation because of the parallel interconnection of parallel devices in layout.
- 2) Netlist extraction by layout vs. schematic
- 3) The resistivity calculation by Calibre CD tool vs. EVDROP custom tool

We can confidently state that the tool's results are very promising, making it a highly effective solution that will



# Conclusions

- ESD checking flow for BCD ST products is a well assessed strategy which has led to tape out hundreds of products releases in the latest years, with positive ESD results during IC qualification
- The EVDROP tool is a support tool to standard verification flow, that operates way before the layout design phase
  - It proactively identifies voltage drop issues along ESD discharge paths
  - Tool results are very promising, making it a highly effective solution that is expected to reduce ESD design verification cycle time and development costs

